

April 2010

FDME510PZT

P-Channel PowerTrench® MOSFET -20 V, -6 A, 37 m Ω

Features

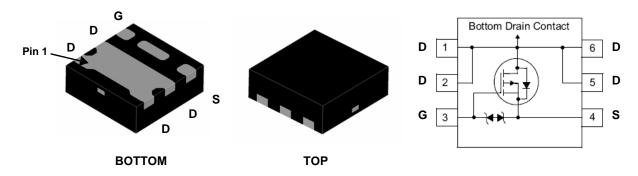
- Max $r_{DS(on)}$ = 37 m Ω at V_{GS} = -4.5 V, I_D = -6 A
- Max $r_{DS(on)}$ = 50 m Ω at V_{GS} = -2.5 V, I_D = -4 A
- Max $r_{DS(on)} = 65 \text{ m}\Omega$ at $V_{GS} = -1.8 \text{ V}$, $I_D = -3 \text{ A}$
- Max $r_{DS(on)} = 100 \text{ m}\Omega$ at $V_{GS} = -1.5 \text{ V}$, $I_D = -2 \text{ A}$
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 2400V (Note3)
- RoHS Compliant



General Description

This device is designed specifically for battery charging or load switching in cellular handset and other ultraportable applications. It features a MOSFET with low on-state resistance.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for its physical size and is well suited to switching and linear mode applications.



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DS}	Drain to Source Voltage		-20	V	
V _{GS}	Gate to Source Voltage			±8	V
1	Drain Current -Continuous	T _A = 25 °C	(Note 1a)	-6	^
'D	-Pulsed			-15	Α
D	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1a)	2.1	14/
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1b)	0.7	W
T _J , T _{STG}	Operating and Storage Junction Temperatu	ıre Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	60	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	175	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
7T	FDME510PZT	MicroFET 1.6x1.6 Thin	FET 1.6x1.6 Thin 7 " 8 mm		5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	ncteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.5	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μA, referenced to 25 °C		3		mV/°C
	$V_{GS} = -4.5 \text{ V}, I_D = -6 \text{ A}$		31	37		
		$V_{GS} = -2.5 \text{ V}, I_D = -4 \text{ A}$		38	50	
rno()	Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -3 \text{ A}$		48	65	mΩ
r _{DS(on)}	Drain to oddree on resistance	$V_{GS} = -1.5 \text{ V}, I_D = -2 \text{ A}$		57	100	11122
		$V_{GS} = -4.5 \text{ V}, I_D = -5 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		40	60	
9 _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -6 \text{ A}$		21		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40.V.V 0.V	1120	1490	pF
C _{oss}	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	155	210	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	140	210	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	.,,	6.5	13	ns
t _r	Rise Time	V_{DD} = -10 V, I_{D} = -6 A V_{GS} = -4.5 V, R_{GEN} = 6 Ω	10	16	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = -4.5 V, K _{GEN} = 612	93	149	ns
t _f	Fall Time		54	86	ns
Q_{g}	Total Gate Charge	V 40.V I 0.A	16	22	nC
Q _{gs}	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, I_{D} = -6 \text{ A}$ $V_{GS} = -4.5 \text{ V}$	1.6		nC
Q_{gd}	Gate to Drain "Miller" Charge	VGS = -4.5 V	4		nC

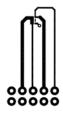
Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.6 \text{ A}$ (Note 2)		-0.6	-1.2	٧
t _{rr}	Reverse Recovery Time	I _F = -6 A, di/dt = 100 A/μs		38	61	ns
Q _{rr}	Reverse Recovery Charge			16	29	nC

Notes: 1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 60 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 175 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < $300\mu s,$ Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

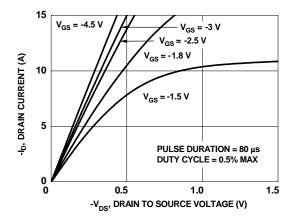


Figure 1. On Region Characteristics

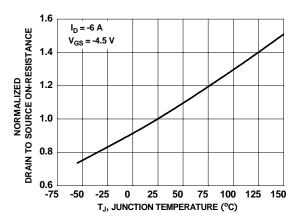


Figure 3. Normalized On Resistance vs Junction Temperature

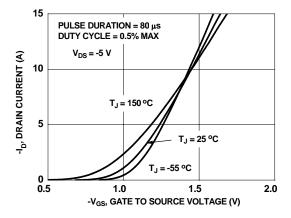


Figure 5. Transfer Characteristics

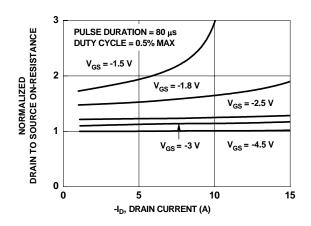


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

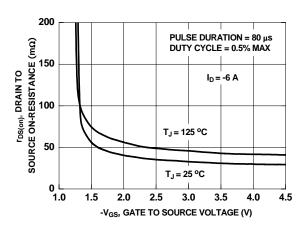


Figure 4. On-Resistance vs Gate to Source Voltage

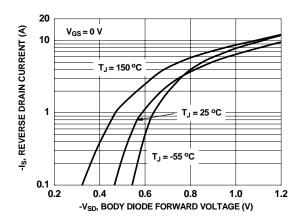


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

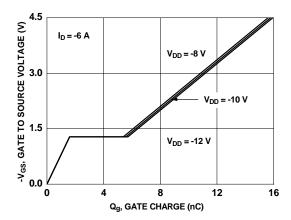


Figure 7. Gate Charge Characteristics

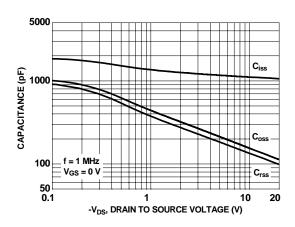


Figure 8. Capacitance vs Drain to Source Voltage

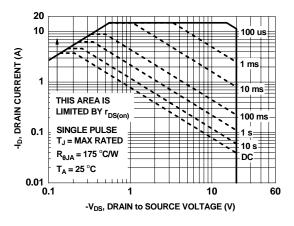


Figure 9. Forward Bias Safe Operating Area

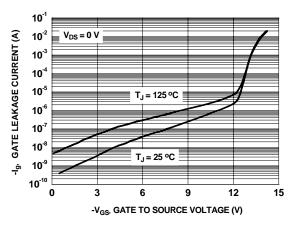


Figure 10. Gate Leakage Current vs Gate to Source Voltage

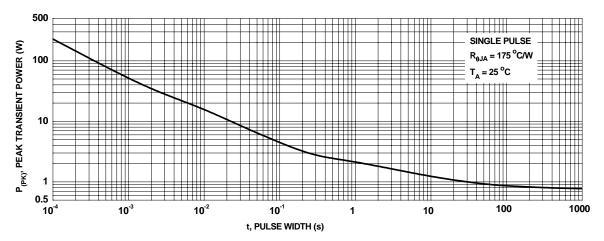


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

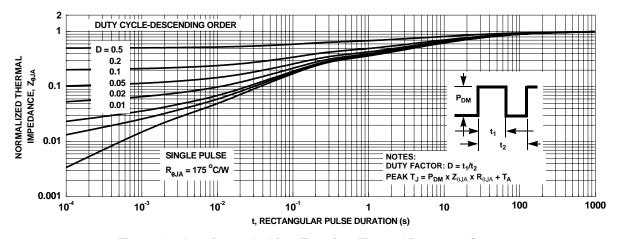
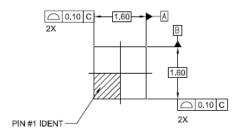
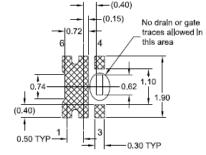


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

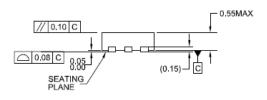
Dimensional Outline and Pad Layout



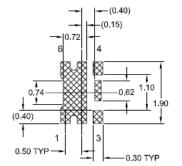
TOP VIEW



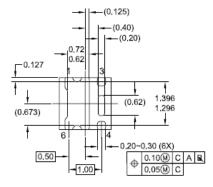
RECOMMENDED LAND PATTERN OPT 1



SIDE VIEW



RECOMMENDED LAND PATTERN OPT 2



BOTTOM VIEW





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